

[54] ULTRASONIC WAVE THICKNESS METER

[75] Inventors: Toyohiko Kitada, Sagamihara; Kunio Iiyama; Kazuyuki Ito, both of Yokohama; Minoru Tamura, Chigasaki; Takanori Arioka, Tokyo, all of Japan

[73] Assignee: Tokyo Keiki Company Limited, Tokyo, Japan

[**] Term: 14 Years

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[52] U.S. Cl. D10/46; D10/78
[58] Field of Search D10/46, 75, 78, 47; 73/597, 431, 432 R

[56]

References Cited

U.S. PATENT DOCUMENTS

D. 189,849	3/1961	Koch	D10/46
D. 213,962	4/1969	Potruch	D10/78
D. 246,956	1/1978	Perry	D10/78
D. 248,734	8/1978	Husseri	D10/46

OTHER PUBLICATIONS

Krautkramer-Brochure-2/76-D-Meter Wall Thickness Gauge.
Metrifast-Flyer-5/24/77-Metal Detector.
Product Engineering-10/78-p. 106-Thickness Gauge at top left.

Primary Examiner-Nelson C. Holtje
Attorney, Agent, or Firm-Haseltine, Lake & Waters

[57]

CLAIM

The ornamental design for an ultrasonic wave thickness meter, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of an ultrasonic wave thickness meter showing our new design;
FIG. 2 is a rear elevational view thereof;
FIG. 3 is a right side elevational view thereof;
FIG. 4 is a left side elevational view thereof;
FIG. 5 is a top plan view thereof; and
FIG. 6 is a bottom plan view thereof.

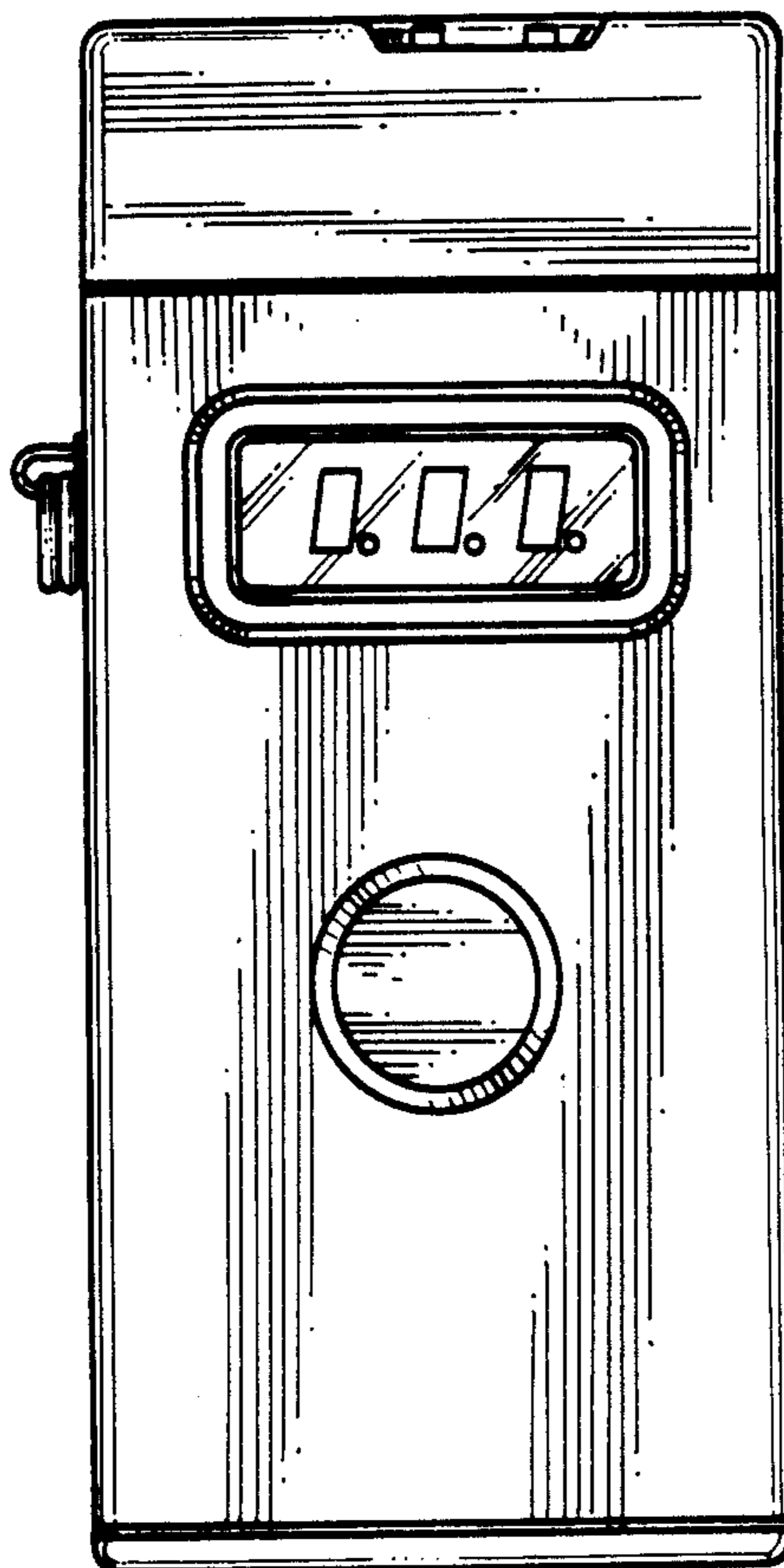


FIG. 1

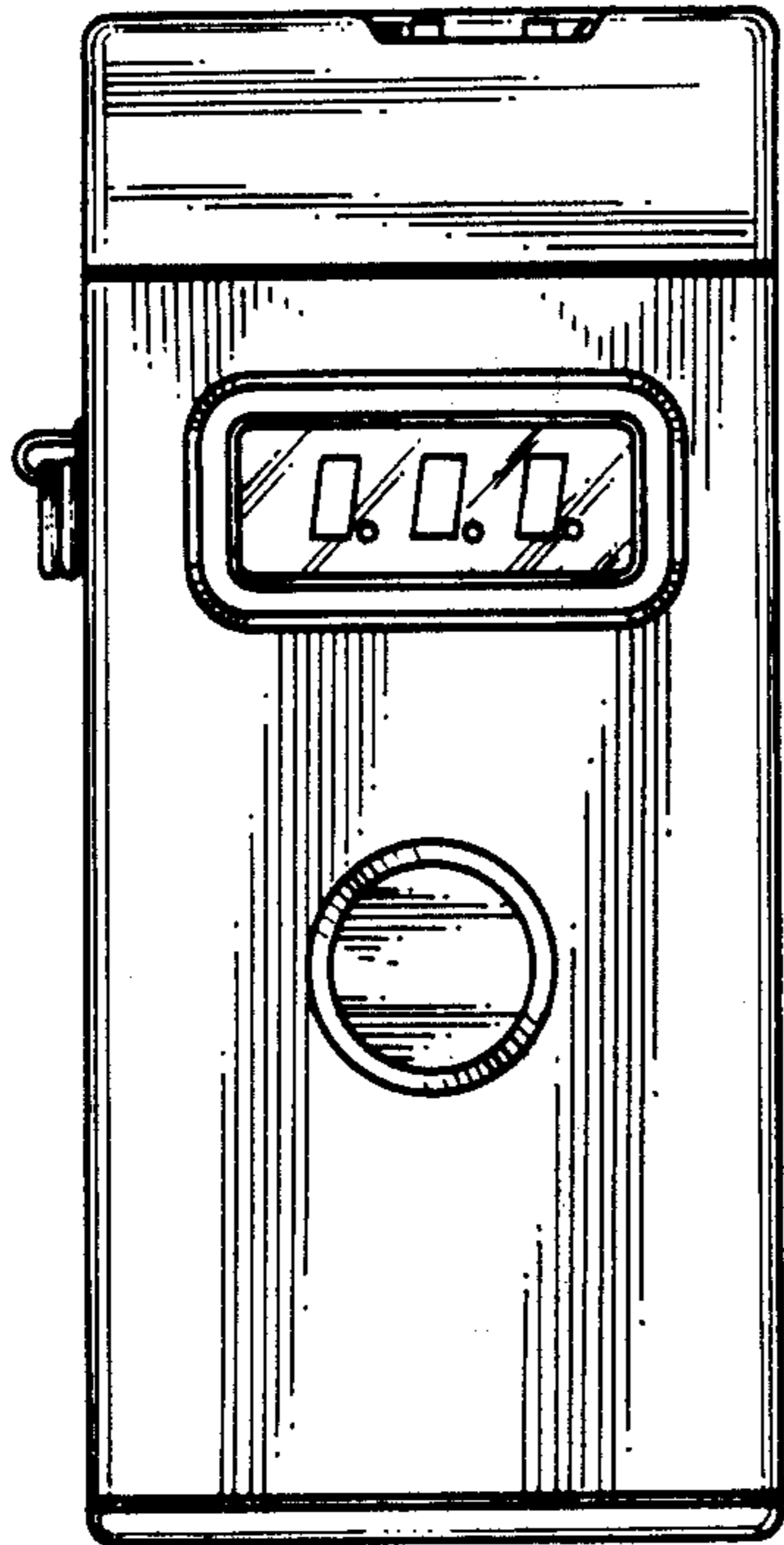


FIG. 2

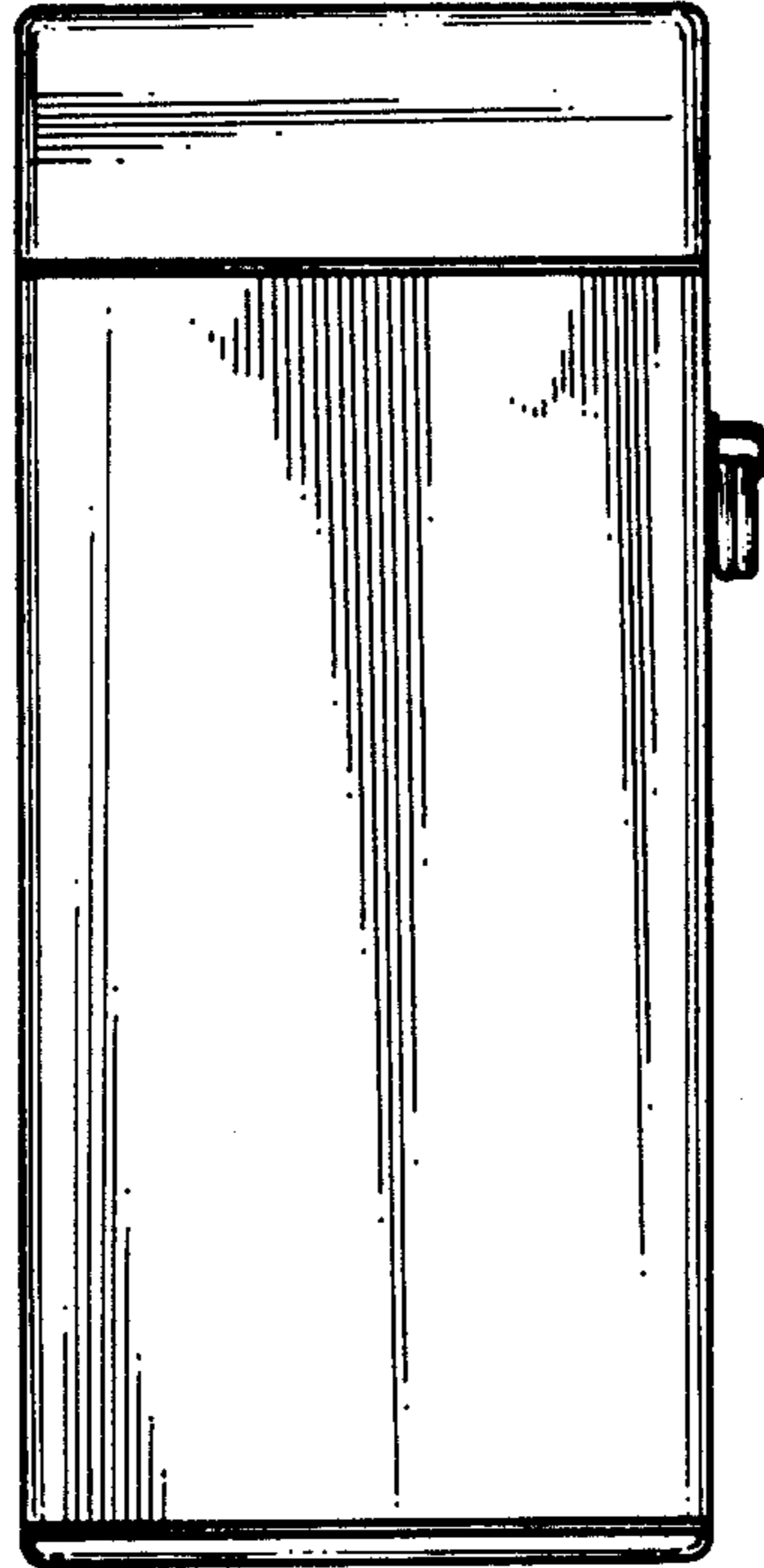


FIG. 3

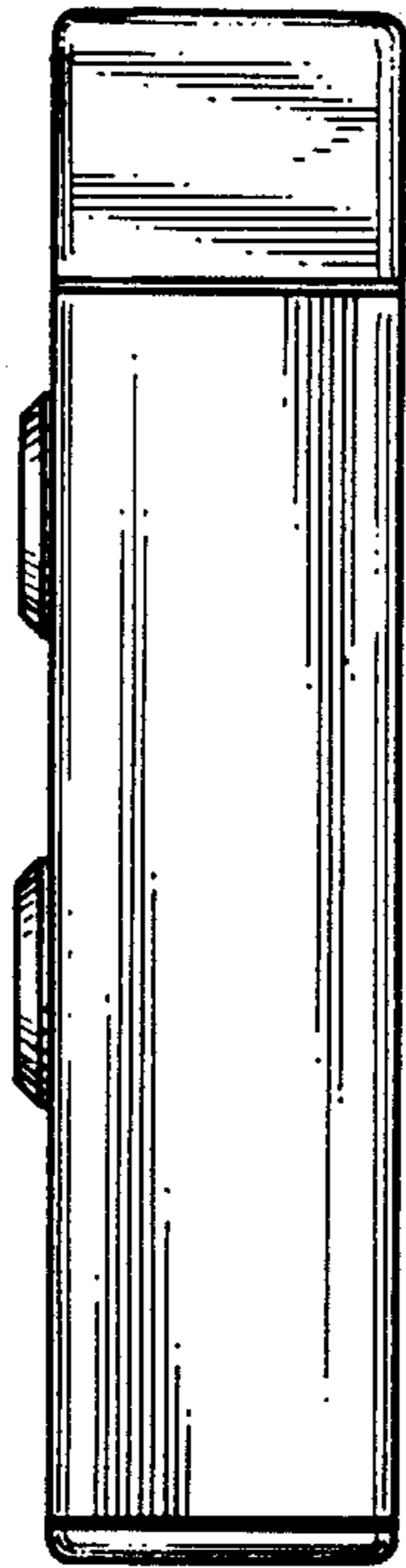


FIG. 4

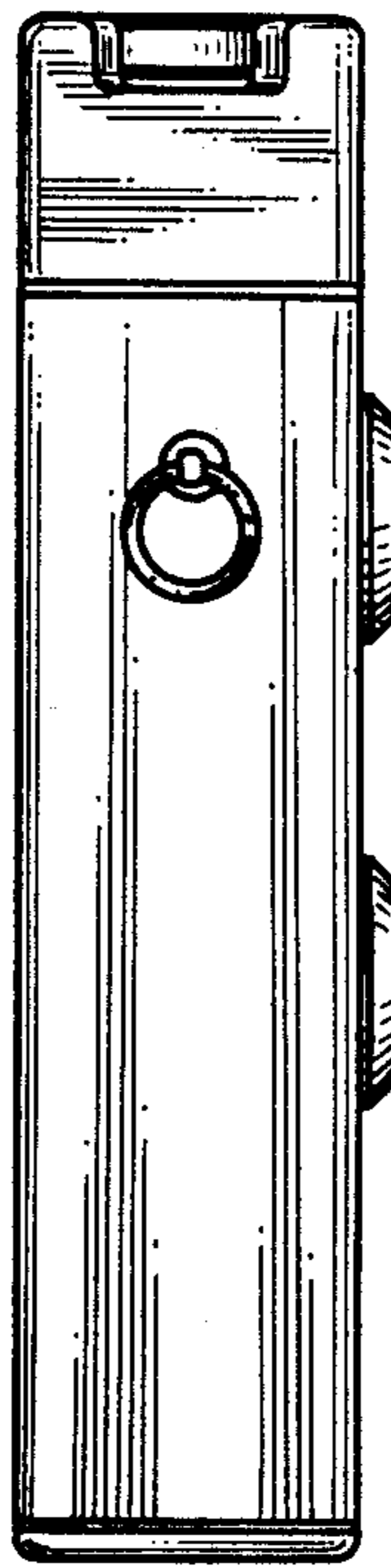


FIG. 5

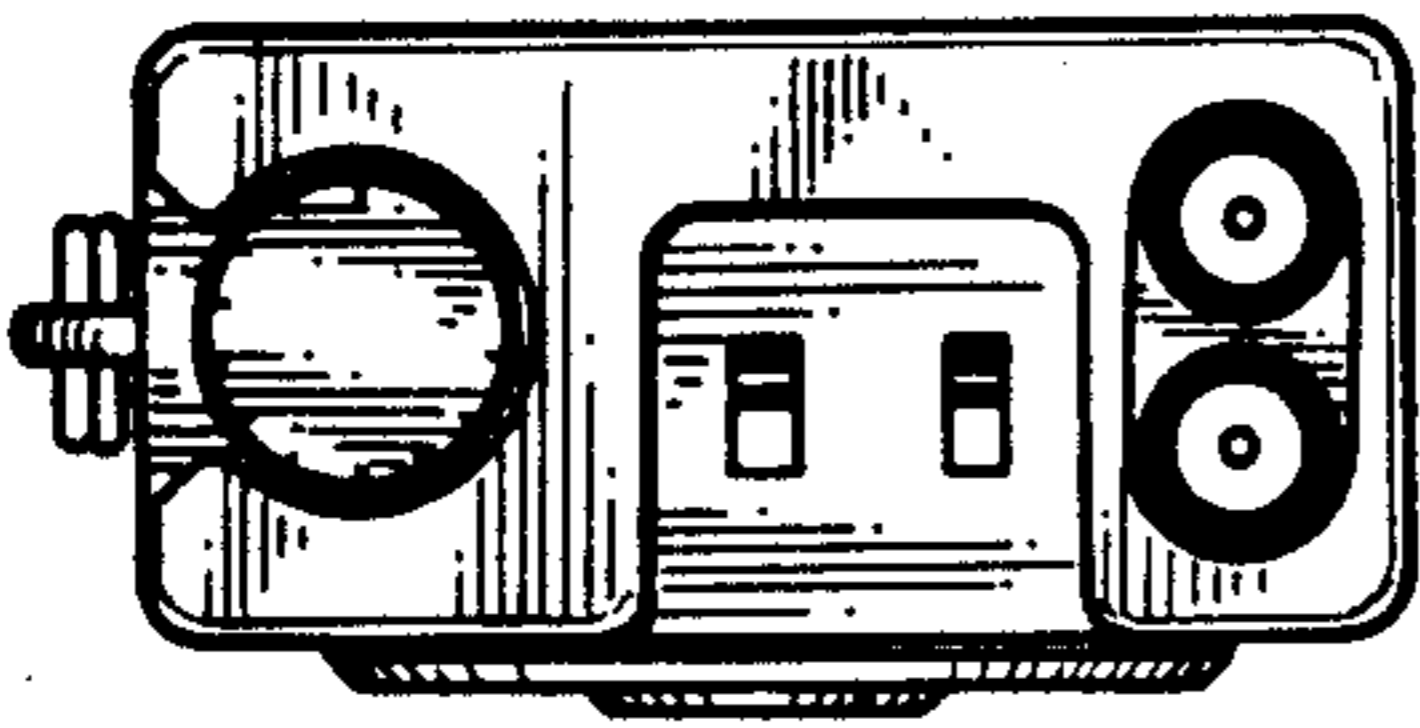


FIG. 6

